Notice of References Cited	Application/Control No. 10/679,982	Applicant(s)/Patent Under Reexamination ALTBERG ET AL.	
	Examiner BINH K. TIEU	Art Unit 2614	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0086104 a1	04-2005	McFadden, Jeffrey A.	705/014
*	B	US-2006/0095343 a1	05-2006	Clarke et al.	705/026
*	C	US-2004/0083133 a1	04-2004	Nicholas et al.	705/014
*	D	US-5,937,390 a	08-1999	Hyodo, Yoshii	705/14
*	E	US-6,470,079 b1	10-2002	Benson, Lonnie John	379/114.13
*	F	US-2005/0251445 a1	11-2005	Wong et al.	705/014
*	G	US-2005/0222908 a1	10-2005	Altberg et al.	705/014
*	H	US-2005/0216345 a1	09-2005	Altberg et al.	705/014
*	I	US-2005/0216341 a1	09-2005	Agarwal et al.	705/014
*	J	US-2005/0165666 a1	07-2005	Wong et al.	705/034
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.